

Test Report

Report No. SCL01J029554001

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Applicant GUANGDONG HOTTECH INDUSTRIAL CO.,LTD
Address NO.183 B HOTTECH INDUSTRIAL ZONE,PUXINHU BUSINESS STREET,TANGXIATOWN,DONGGUAN CITY,GUANGDONG PROVINCE

The following sample(s) and sample information was/were submitted and identified by/on the behalf of the client

Sample Name diodes and transistors
 Client Reference SOT-23/323/523/723/363/223/23-5/23-6/89 TO-92/92L/126/252/251/220
 Information SOD-123/323/523/723 SMA/SMB/SMC/**SMAE/SMBF**
 Sample Received Date May 12, 2017
 Testing Period May 12, 2017 to May 18, 2017

Test Requested As specified by client, to test Lead (Pb), Cadmium (Cd), Mercury (Hg), Hexavalent Chromium(Cr(VI)), Polybrominated Biphenyls(PBBs), Polybrominated Diphenyl Ethers(PBDEs) in the submitted sample(s).

Test Method

Test Item(s)	Test Method	Measured Equipment(s)
Lead (Pb)	IEC 62321-5:2013 Ed.1.0	ICP-OES
Cadmium (Cd)	IEC 62321-5:2013 Ed.1.0	ICP-OES
Mercury (Hg)	IEC 62321-4:2013 Ed.1.0	ICP-OES
Hexavalent Chromium(Cr(VI))	IEC 62321:2008 Ed.1 Annex C	UV-Vis
Polybrominated Biphenyls(PBBs)	IEC 62321-6:2015	GC-MS
Polybrominated Diphenyl Ethers(PBDEs)	IEC 62321-6:2015	GC-MS

Test Result(s) Please refer to the following page(s).



Tested by Jim Yi
 Approved by Hill Zheng
 Hill Zheng
 Technical Manager

Reviewed by Tori Xia
 Date May 18, 2017

No. R289323341

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